Notice of References Cited Application/Control No. 10/708,949 Examiner David G. Cervetti Applicant(s)/Patent Under Reexamination FAN ET AL. Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,077,790 A	12-1991	D'Amico et al.	380/249
*	В	US-5,557,679 A	09-1996	Julin et al.	380/249
*	С	US-6,144,949 A	11-2000	Harris, Michael Gilbert	705/38
*	D	US-2002/0012433 A1	01-2002	Haverinen et al.	380/247
*	E	US-2002/0021809 A1	02-2002	Salo et al.	380/239
*	F	US-2002/0034301 A1	03-2002	Andersson, Stefan	380/270
*	G	US-2002/0035687 A1	03-2002	Skantze, Kristofer	713/168
*	Н	US-2002/0056044 A1	05-2002	Andersson, Stefan	713/189
*	1	US-2002/0059530 A1	05-2002	Talvitie, Olli	713/201
*	J	US-2002/0083320 A1	06-2002	Vatanen, Harri	713/168
*	К	US-2002/0097876 A1	07-2002	Harrison, Keith Alexander	380/270
*	L	US-6,484,260 B1	11-2002	Scott et al.	713/186
*	М	US-2002/0169958 A1	11-2002	Nyman et al.	713/168

FOREIGN PATENT DOCUMENTS

*	·	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р				·	
	Q	•			·	
	R					
	S					
	Τ					

NON-PATENT DOCUMENTS

		HON-PAILINE DOCUMENTS
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/708,949 Examiner David G. Cervetti Applicant(s)/Patent Under Reexamination FAN ET AL. Art Unit Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0028805 A1	02-2003	Lahteenmaki, Markku	713/201
* .	В	US-2003/0079124 A1	04-2003	Serebrennikov, Oleg	713/156
*	С	US-2003/0070084 A1	04-2003	Satomaa et al.	713/200
*	۵	US-2003/0114191 A1	06-2003	Nishimura, Hiroaki	455/557
*	E	US-2003/0147532 A1	08-2003	Hakkarainen et al.	380/239
*	F	US-2003/0158807 A1	08-2003	Takeshi, Yoneda	705/37
*	G	US-2003/0150915 A1	08-2003	Reece, Kenneth	235/449
*	Н	US-2003/0172278 A1	09-2003	Farnham et al.	713/176
*	1	US-2003/0204726 A1	10-2003	Kefford et al.	713/171
*	J	US-2003/0210789 A1	11-2003	Farnham et al.	380/270
*	K	US-2003/0236985 A1	12-2003	Ruuth, Anna-Leena	713/173
*	L	US-2004/0013269 A1	01-2004	Du et al.	380/284
*	М	US-6,721,886 B1	04-2004	Uskela, Sami	713/168

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country .	Name	Classification
	Z					
	0				·	
	P					
i	Q	·				
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	٦	
	V	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/708,949 Examiner David G. Cervetti Applicant(s)/Patent Under Reexamination FAN ET AL. Art Unit Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0102987 A1	05-2004	Takahashi et al.	705/001
*	В	US-2004/0117623 A1	06-2004	Kalogridis et al.	713/165
*	С	US-2004/0136529 A1	07-2004	Rhelimi et al.	380/044
*	D	US-2004/0158716 A1	08-2004	Turtiainen et al.	713/172
*	Ε	US-6,799,155 B1	09-2004	Lindemann et al.	703/24
*	F	US-2004/0240671 A1	12-2004	Hu et al.	380/277
*	G	US-2005/0069137 A1	03-2005	Landrock, Peter	380/278
*	Н	US-6,883,052 B2	04-2005	Dorenbeck et al.	710/200
*	ı	US-2005/0086496 A1	04-2005	Sandberg, Leif	713/185
*	J	US-6,880,079 B2	04-2005	Kefford et al.	713/155
*	К	US-2005/0120225 A1	06-2005	Kirsch et al.	713/183
*	L	US-2005/0147249 A1	07-2005	Gustavsson et al.	380/247
*	М	US-6,930,987 B1	08-2005	Fukuda et al.	370/328

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	·				· ·
	Q					
	R	·				
	S				•	
	Ť				· · · · · · · · · · · · · · · · · · ·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/708,949 Examiner David G. Cervetti Applicant(s)/Patent Under Reexamination FAN ET AL. Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name [Classification
*	Α	US-2005/0222949 A1	10-2005	Inotay et al.	705/040
*	В	US-7,010,694 B2	03-2006	Vatanen, Harri	713/176
*	O	US-7,107,620 B2	09-2006	Haverinen et al.	726/29
*	D	US-7,114,175 B2	09-2006	Lahteenmaki, Markku	726/4
*	E	US-7,151,922 B2	12-2006	Sashihara et al.	455/412.2
*	F	US-7,231,372 B1	06-2007	Prange et al	705/67
*	G	US-7,231,531 B2	06-2007	Cupps et al.	713/322
	Н	US-			
	1	US-			
	J	US-			
	К	US-		•	
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	. Name	Classification
	Ν					
	0					
	Р			•		
	Q	·				
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.